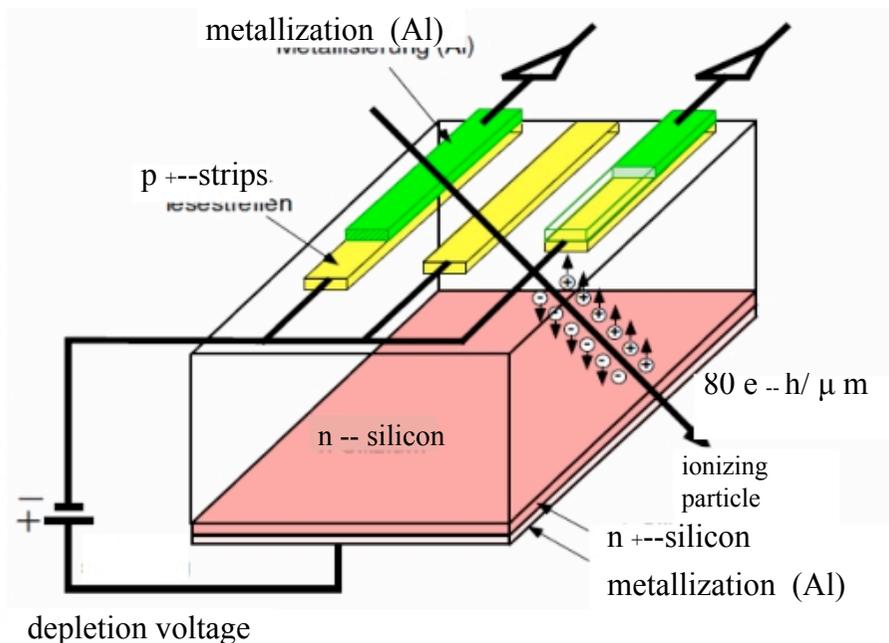


# Strip Detectors

- First detector devices using the lithographic capabilities of microelectronics
- First Silicon detectors -- > strip detectors
- Can be found in all high energy physics experiments of the last 20 years

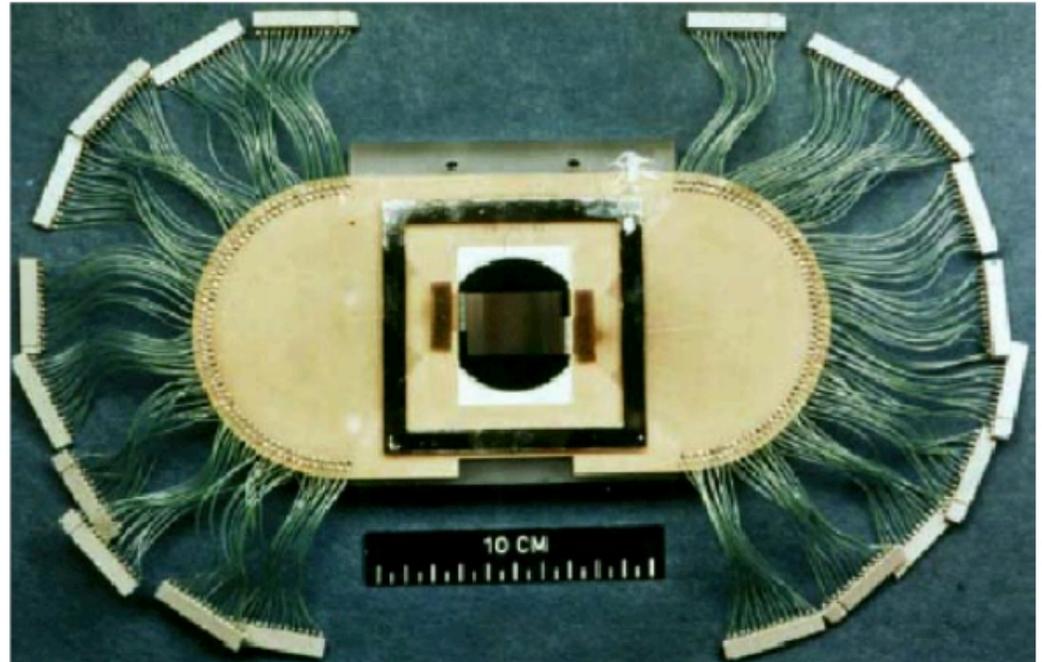


Principal: Silicon strip detector

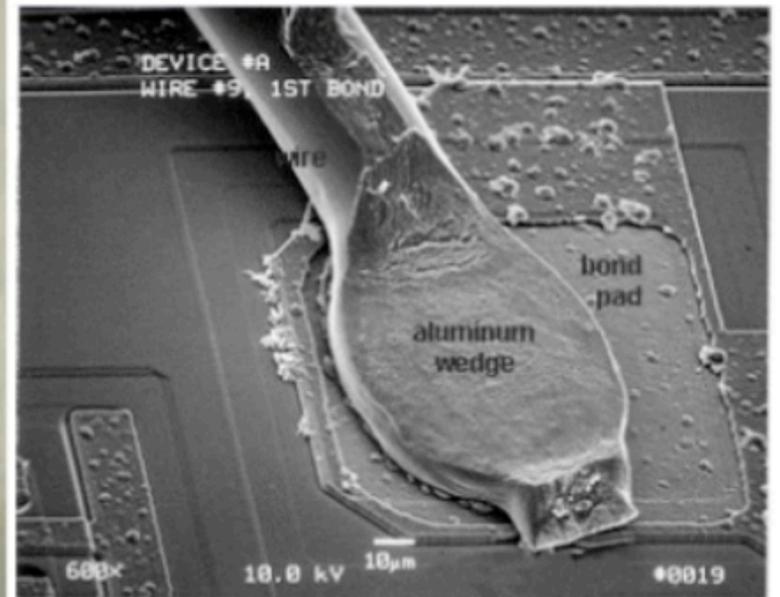
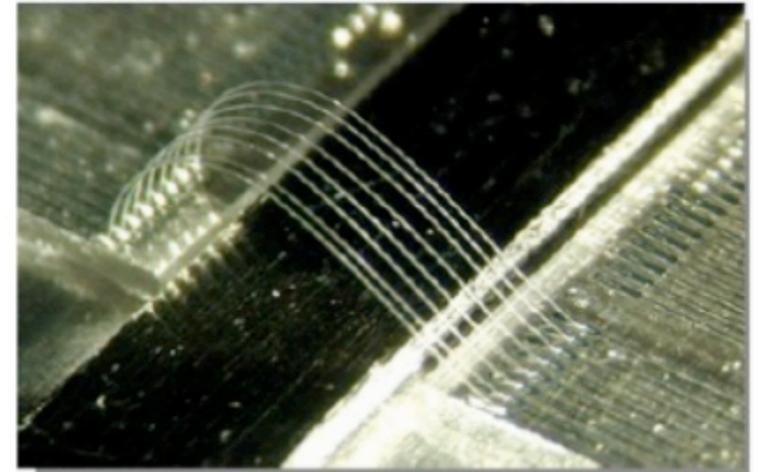
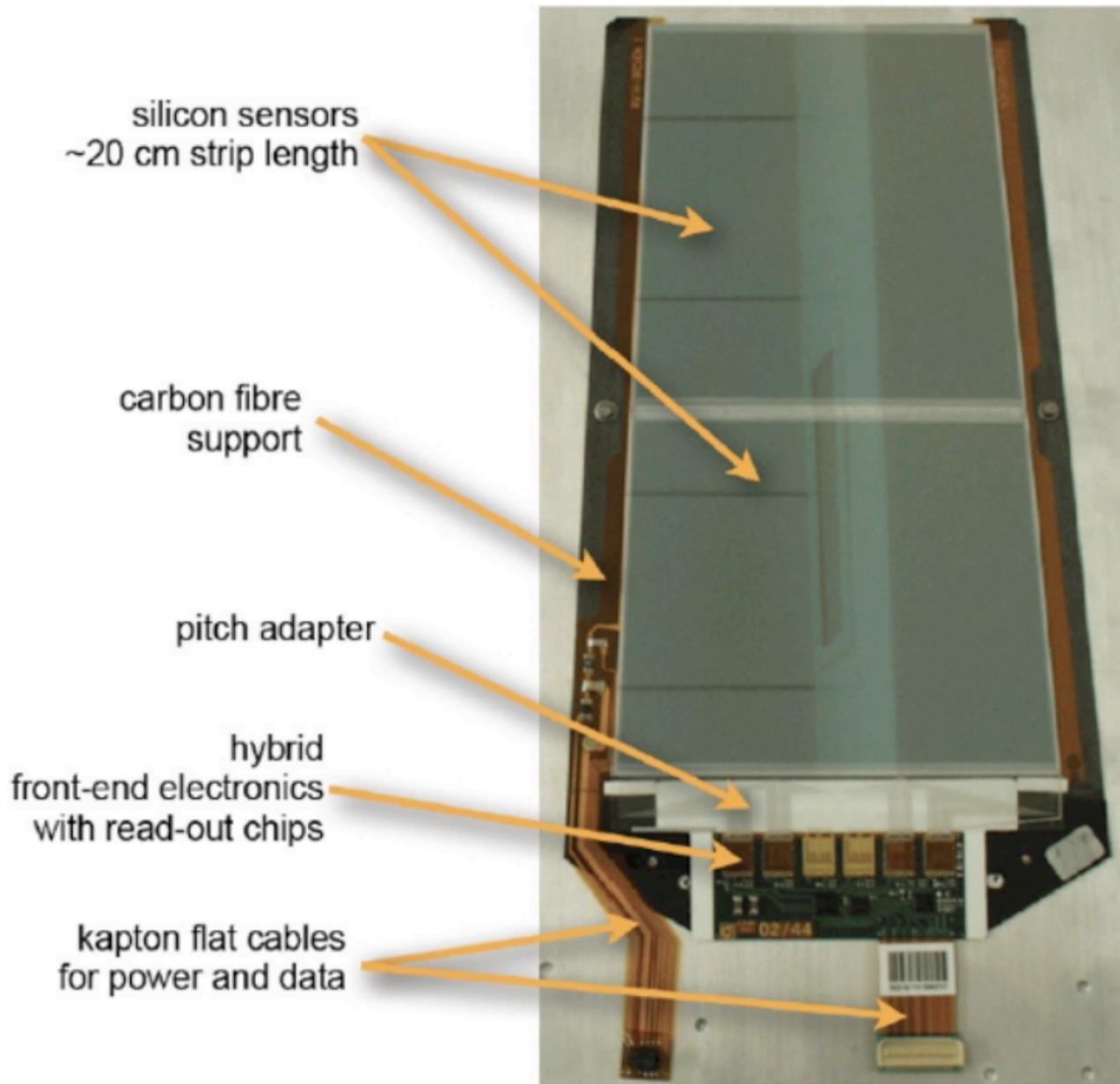
- Arrangement of strip implants acting as charge collecting electrodes.
- Placed on a low doped fully depleted silicon wafer these implants form a one-dimensional array of diodes
- By connecting each of the metalized strips to a charge sensitive amplifier a position sensitive detector is built.
- Two dimensional position measurements can be achieved by applying an additional strip like doping on the wafer backside (double sided technology)

# First HEP Application: NA11

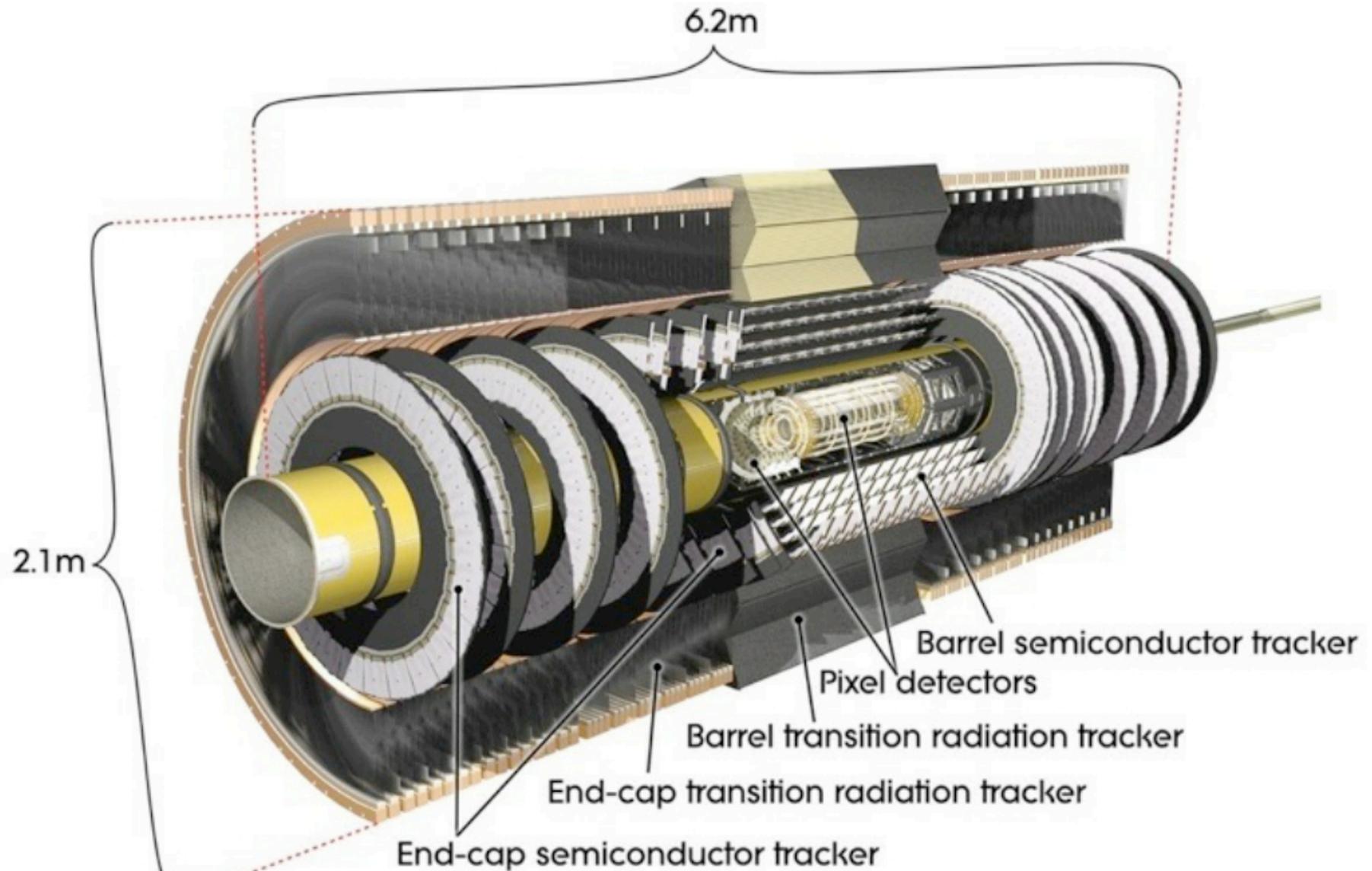
- After discovery of charm (1974),  $\tau$  -- lepton (1975) and beauty (1977) with lifetimes  $c\tau \sim 100 \mu\text{m}$  : need fast (ns), and precise ( $\mu\text{m}$ ) electronic tracking detectors
- strip detector for NA11 in 1981
  - 1200 strip-- diodes
  - 20  $\mu\text{m}$  pitch
  - 60  $\mu\text{m}$  readout pitch
  - 24 x 36  $\text{mm}^2$  active area  $\sim 0.01\text{m}^2$
  - position resolution  $\sim 5.4 \mu\text{m}$
  - 8 layer at the start
- precise track reconstruction
- readout electronic:  $\sim 1\text{m}^2$ !



# Strip Module CMS



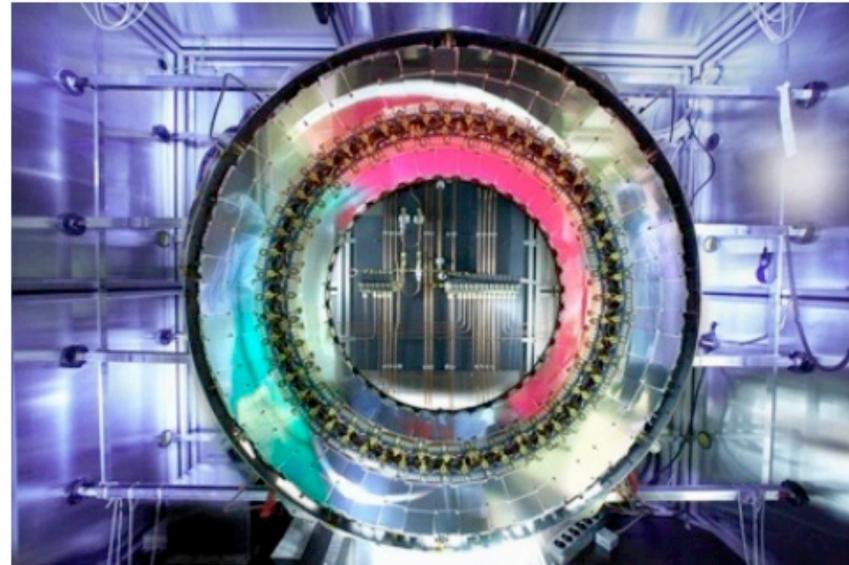
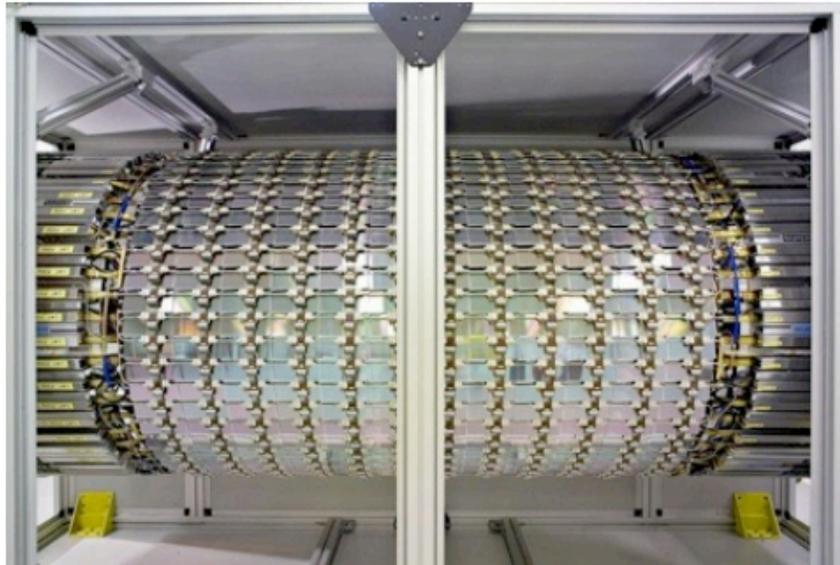
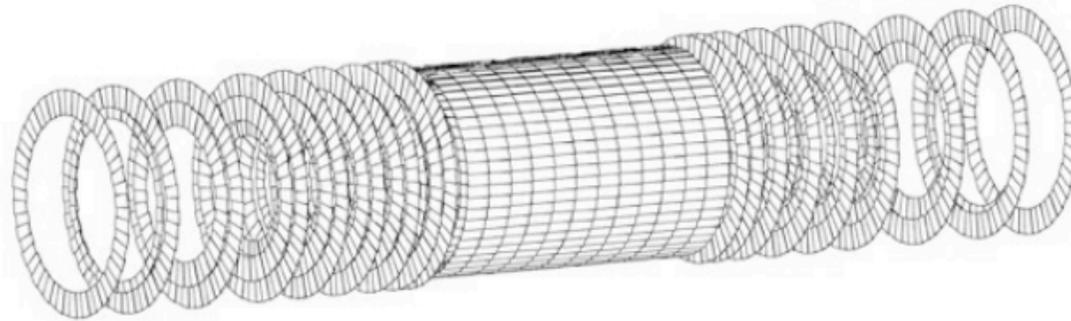
# ATLAS SCT



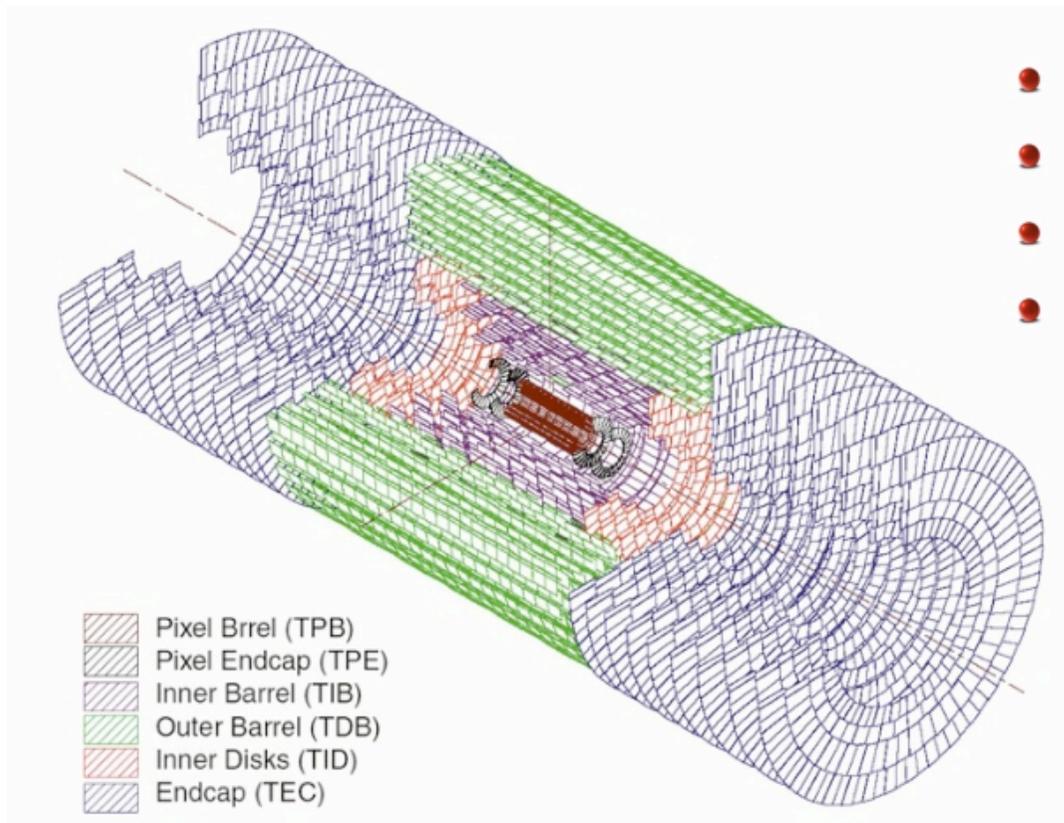
Si-- strips: 4 Barrel--layer, 2 x 9 discs

# ATLAS SCT

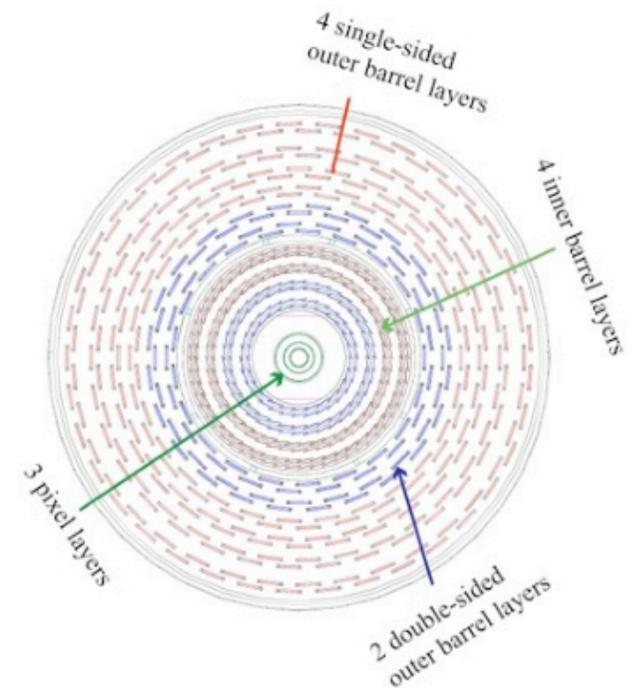
- 61 m<sup>2</sup> silicon, ~6.2 M channels
- 4088 modules, 2112 barrel (1 type), 1976 in the discs (4 different types)



# CMS Si --Tracker

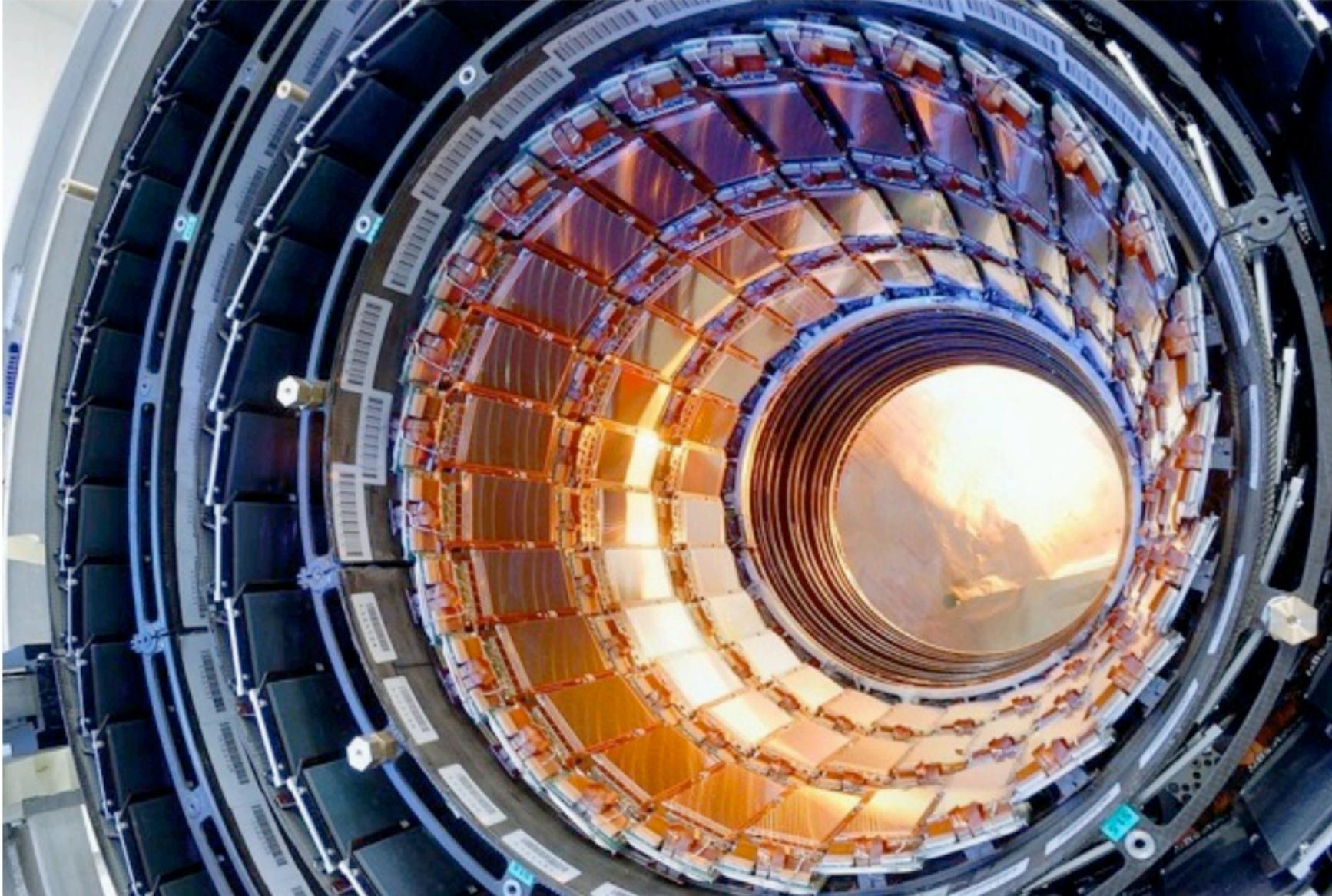


- ~ 210 m<sup>2</sup> Silicon
- 25 000 Sensors, 9.6 M channels
- 10 barrel layers, 2x 9 discs
- The largest silicon tracker ever built



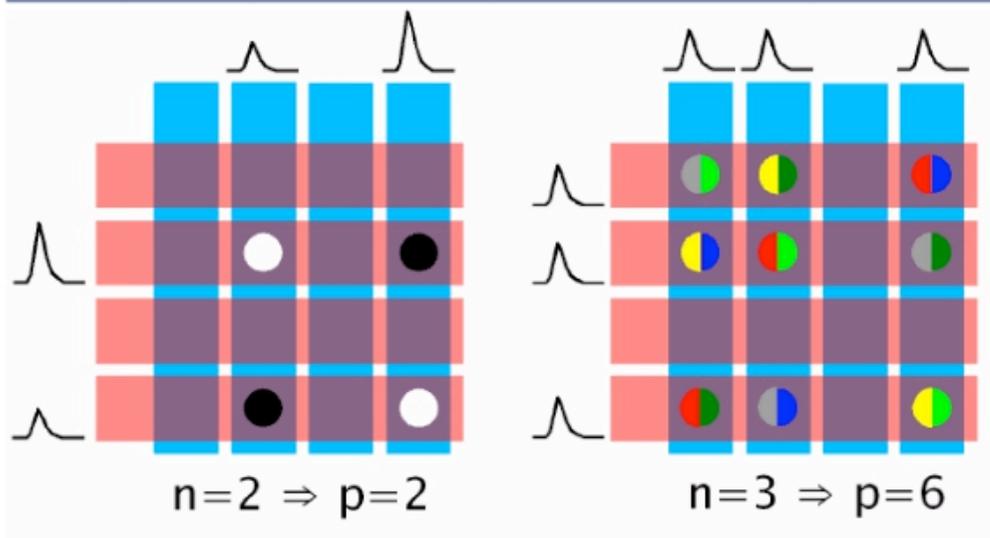
# CMS Tracker -- Beauty Shot

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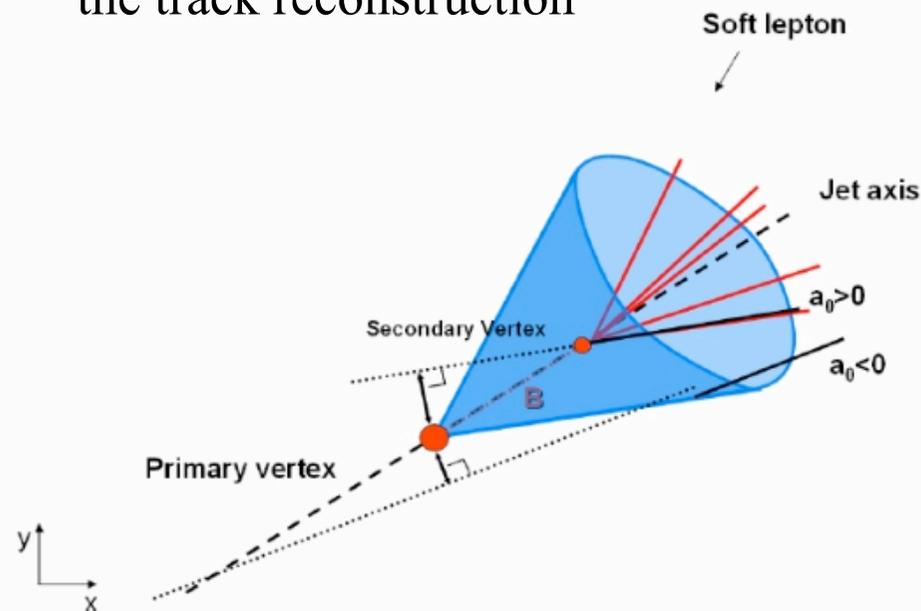


Pic:CERN

# Limits of Strip Detectors



- In case of high particle fluences ambiguities give difficulties for the track reconstruction

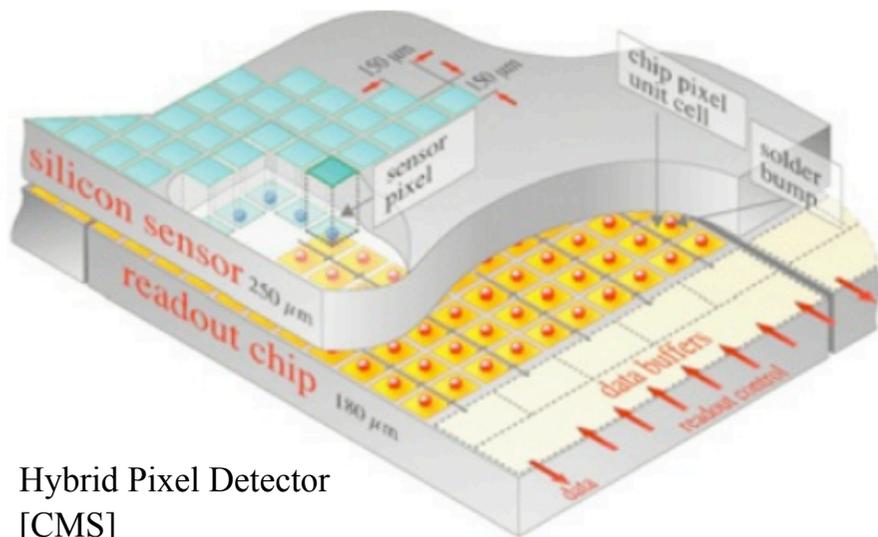
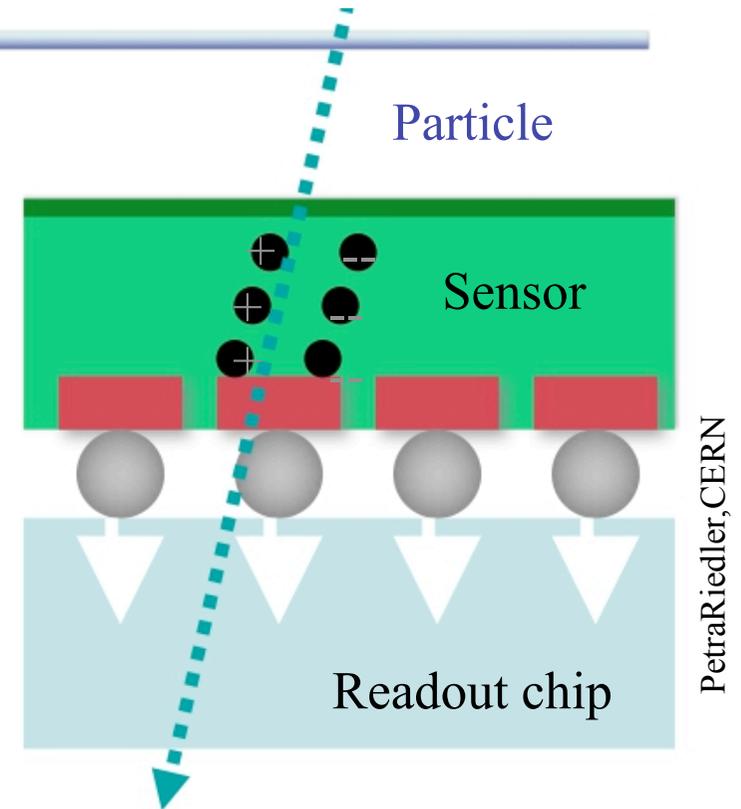


- Deriving the point resolution from just one coordinate is not enough information to reconstruct a secondary vertex
- Pixel detectors allow track reconstruction at high particle rate without ambiguities
- Good resolution with two coordinates (depending on pixel size and charge sharing between pixels)
  - ▶ Very high channel number: complex read-out
  - ▶ Readout in active area a detector

**First pixels (CCDs)  
in NA11/NA32: ~1983**

# Hybrid Pixels – “classical ” Choice HEP

- The read-- out chip is mounted directly on top of the pixels (bump-- bonding)
- Each pixel has its own read-- out amplifier
- Can choose proper process for sensor and read-- out separately
- Fast read-- out and radiation-- tolerant
- ... **but:**
- **Pixel area defined** by the size of the read-- out chip
- **High material budget** and high power dissipation

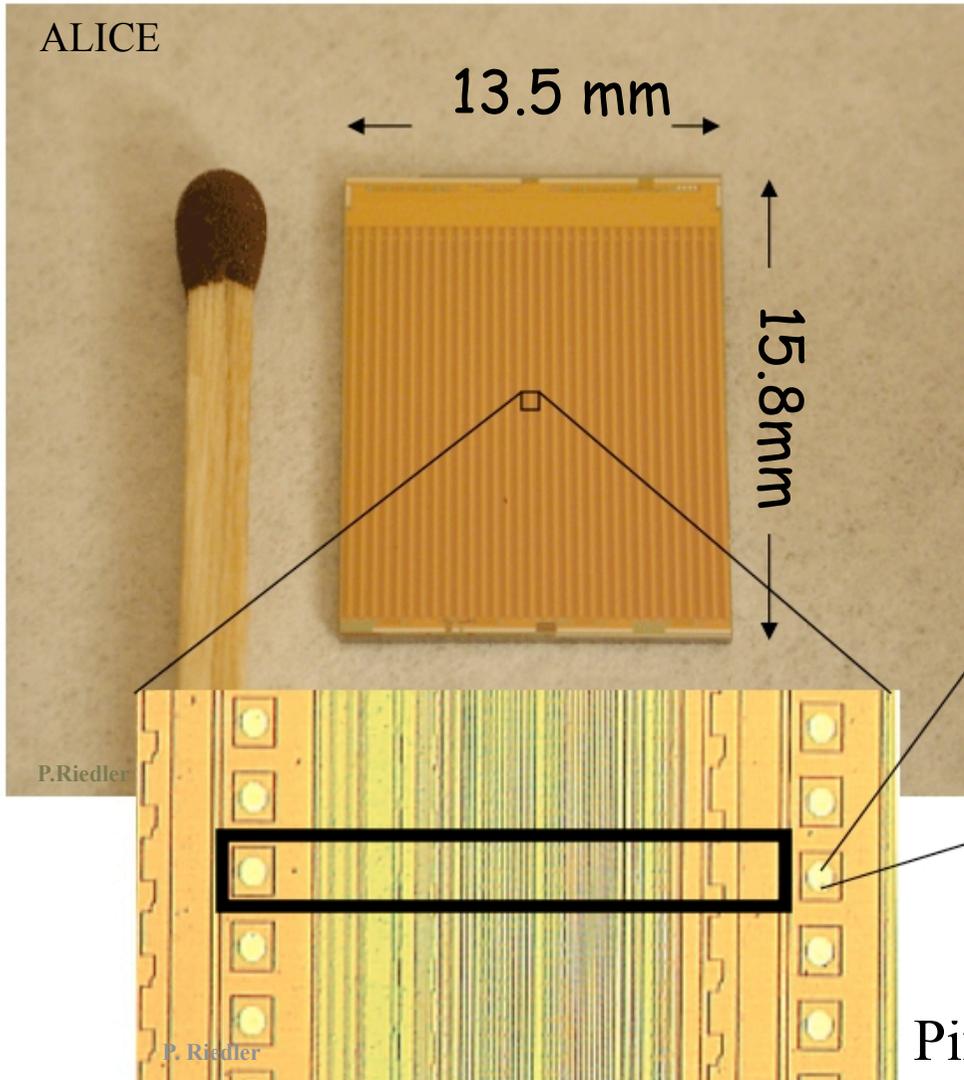


Hybrid Pixel Detector  
[CMS]

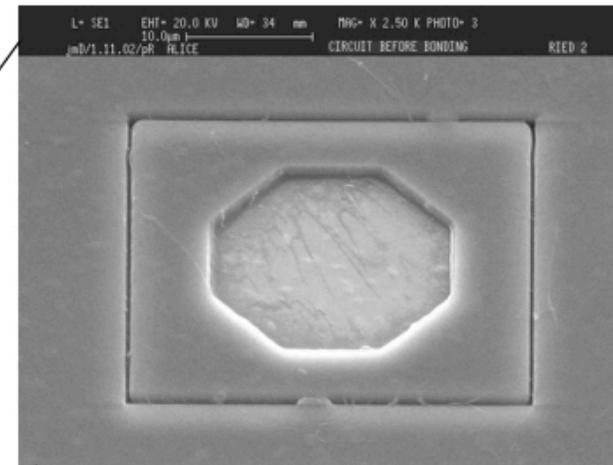
- CMS Pixels: ~65 M channels  
100 μm x 150 μm
- ATLAS Pixels: ~80 M channels  
50 μm x 400 μm (long in z or r)
- Alice: 50 μm x 425 μm
- LHCb
- Phenix
- ....

# Hybrid Pixel Chip

FE chip



ASIC, custom design

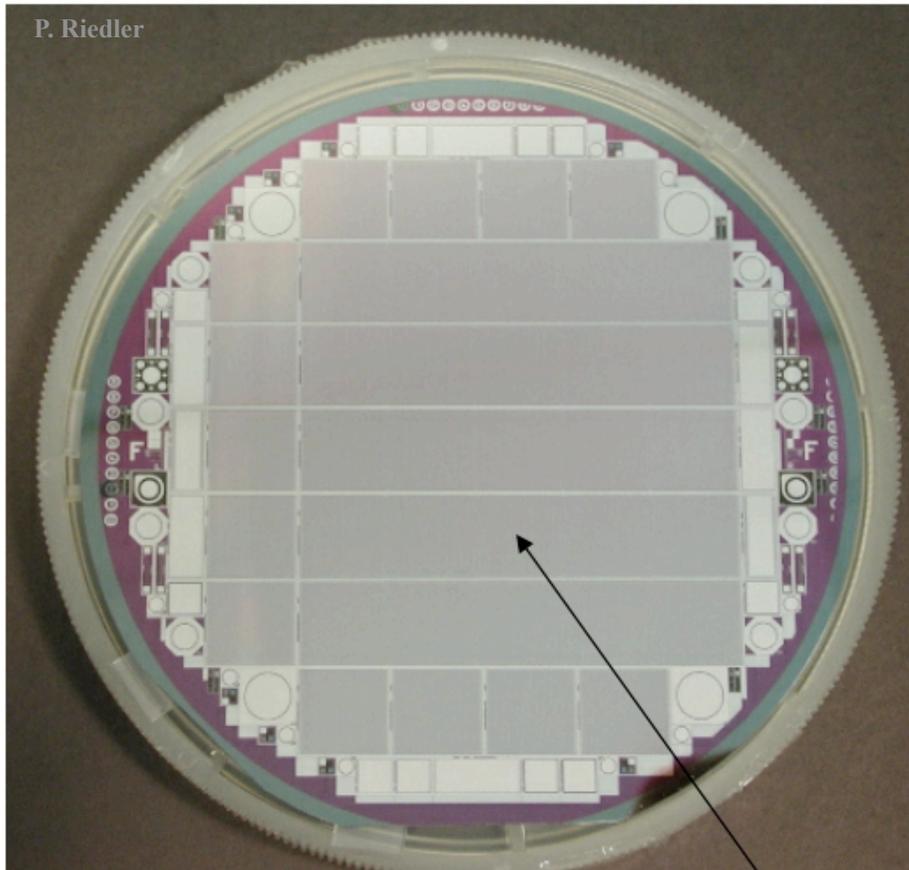


Bump bonding pad

Pixel cell (e.g.  $50 \mu\text{m} \times 425 \mu\text{m}$ )

# Pixel Sensor

FE chip



Different sensor materials can be used: Si, CdTe , GaAs, ...

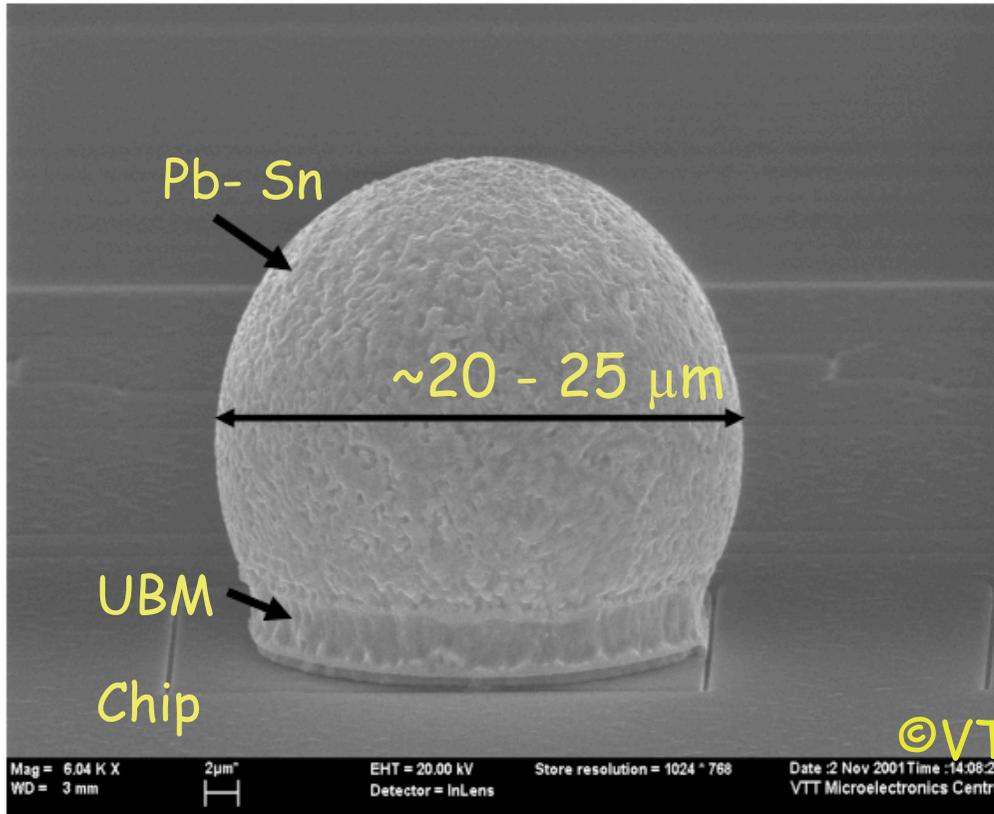
Depending on application (tracking, single photon counting, ..)

Usually several readout chips are connected to one sensor.

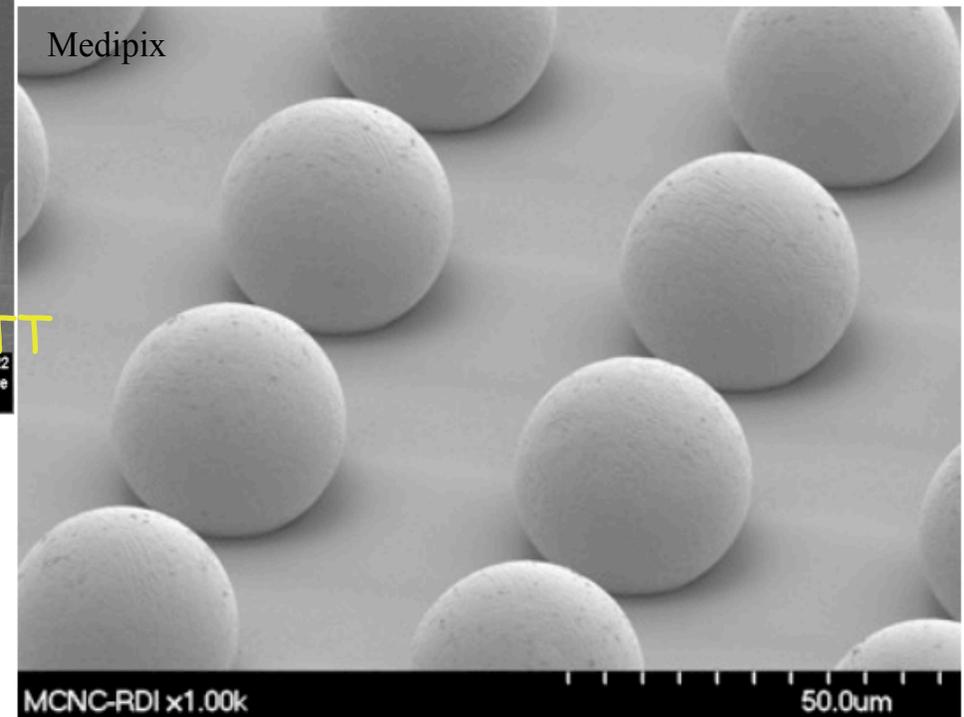
Pixel cell (50µm x 425µm)

# Bump Bond

FE chip

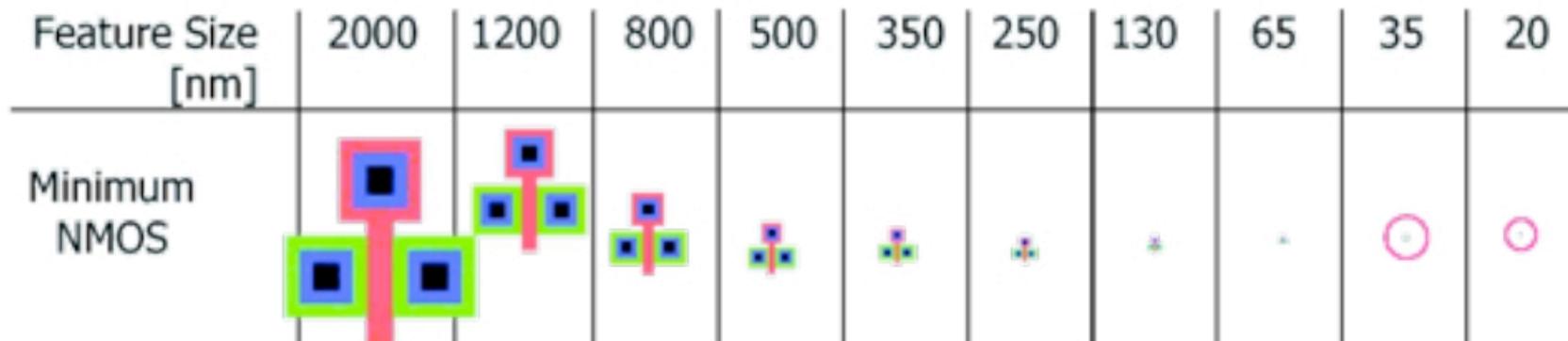
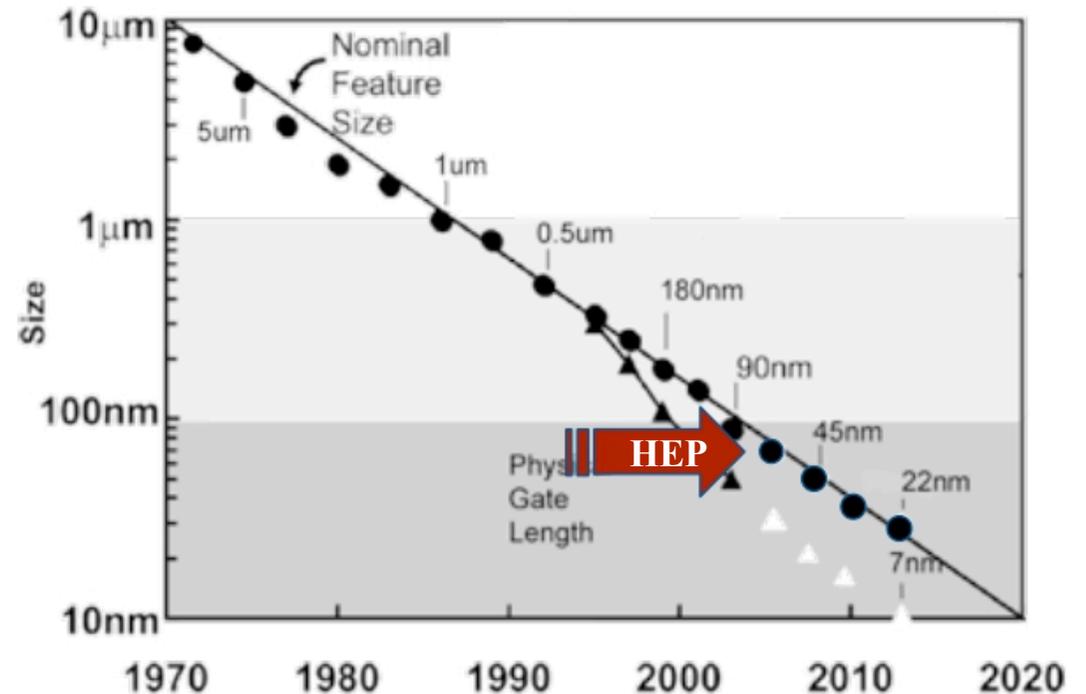


SEM picture of one Pb --Sn bump bond



# Industry Scaling Roadmap

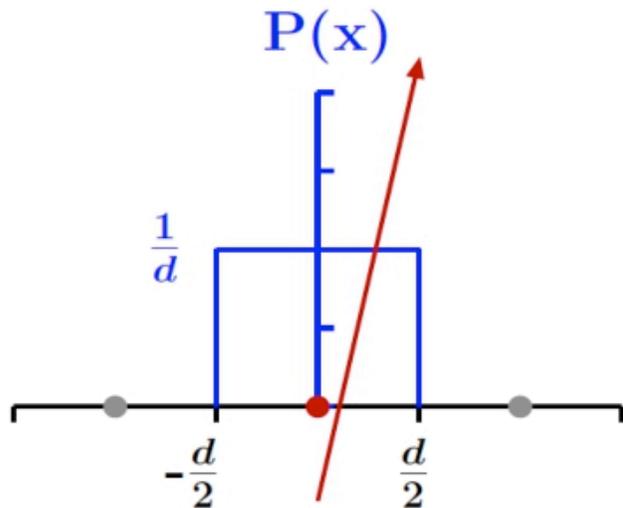
- New generation every  $\sim 2$  years
- From 1970 (8  $\mu\text{m}$ ) to 2013 (22 nm) (industrial application)
- HEP nowadays at 130nm and 65nm
- Problem: by the time a technology is ready for HEP --  $\rightarrow$  “old” in industry standards.



# Resolution of Tracking Detectors

- Depending on detector geometry and charge collection
- Strip pitch
- Charge sharing between strips

Simple case: all charge is collected in one strip



- Simple case: all charge is collected by one strip
  - Traversing particle creates signal in hit strip
  - Flat distribution along strip pitch; no area is pronounced
- ➔ Probability distribution for particle passage:

$$P(x) = \frac{1}{d} \quad \Rightarrow \quad \int_{-d/2}^{d/2} P(x) dx = 1$$

The reconstructed point is always the middle of the strip:

$$\langle x \rangle = \int_{-d/2}^{d/2} x P(x) dx = 0$$

# Resolution of Tracking Detectors II

---

- Calculating the resolution orthogonal to the strip:

$$\sigma_x^2 = \langle (x - \langle x \rangle)^2 \rangle = \int_{-d/2}^{d/2} x^2 P(x) dx = \frac{d^2}{12}$$

- Resulting in a general term (also valid for wire chambers):

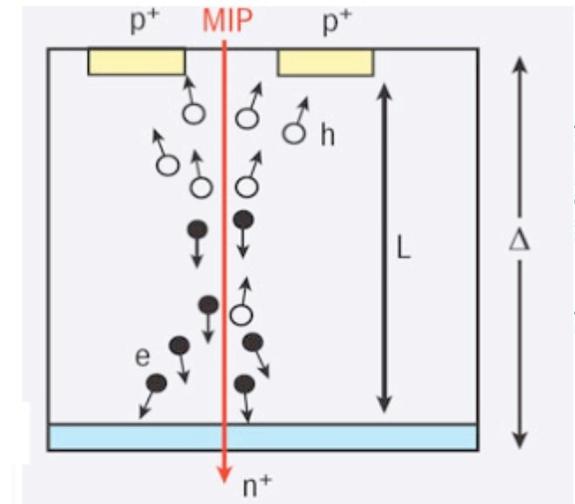
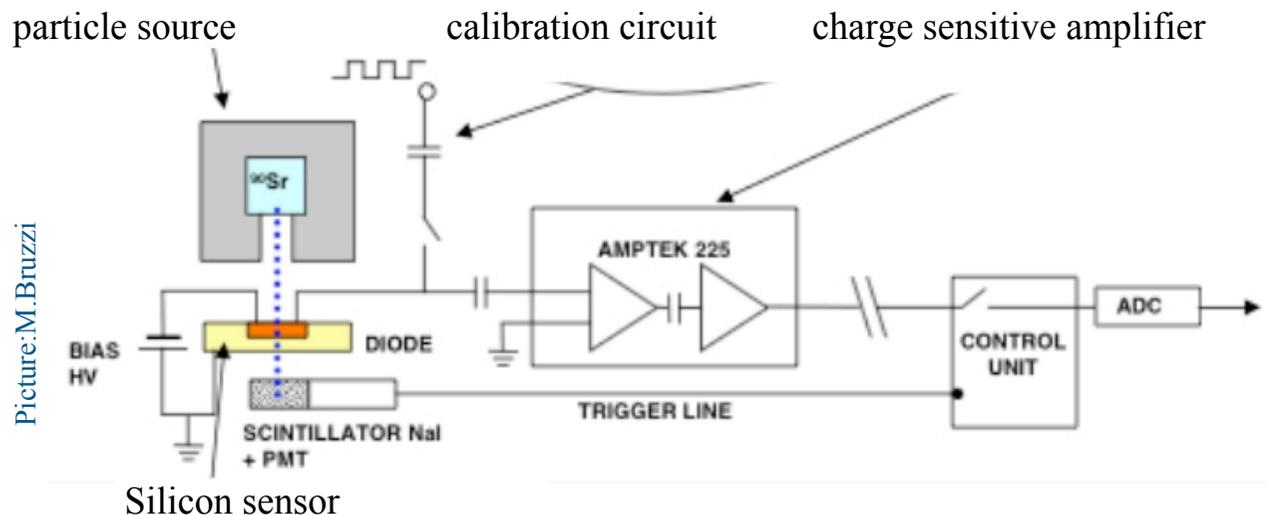
$$\sigma = \frac{d}{\sqrt{12}}$$

- For a silicon strip detector with a strip pitch of 80  $\mu\text{m}$  this results in a minimal resolution of  $\sim 23\mu\text{m}$
- In case of charge sharing between the strip (signal size decreasing with distance to hit position)
- Resolution improved by center of gravity calculation

# Charge Collection

- Collected charge in a detector volume
  - important parameter which shows effects with radiation damage or other effects
  - charge induced by particles from a radioactive source, by a laser or test beam particles
  - measurement of CC in comparison to optimal value versus different parameters (**CC efficiency**)
    - bias voltage
    - radiation level
    - ....

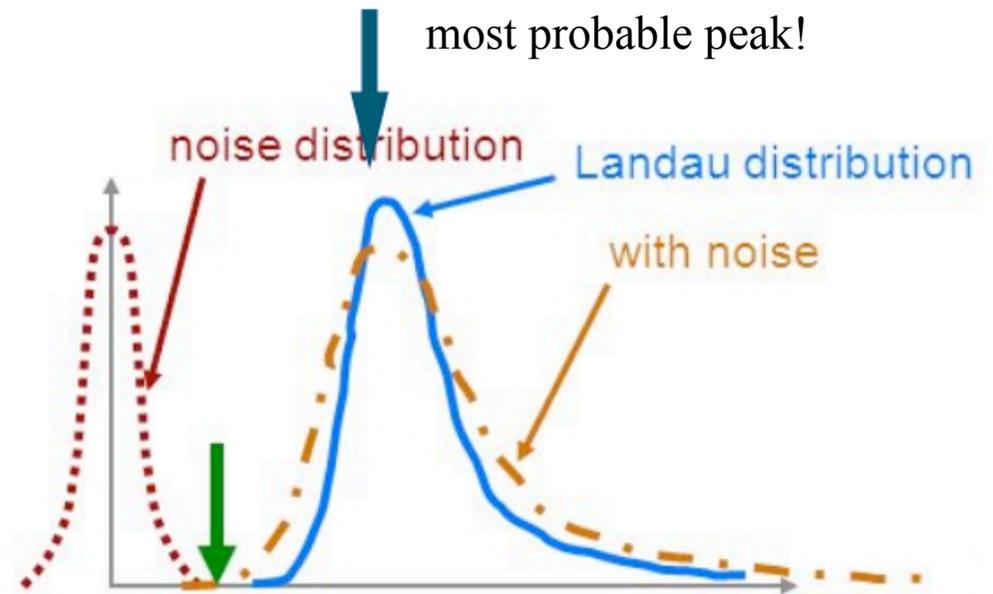
## Example: with $^{90}\text{Sr}$ source



Can be measured with bench top setup in a laboratory

# Signal/Noise Ratio

- Signal size for a certain input signal over the intrinsic noise of the detector
- parameter for analog signals
- good understanding of electrical noise needed
  - noise measurements
  - noise simulations
- signal induced by source or laser (or test beam particles)
- optimal S/N is larger than 20



# Detection Efficiency

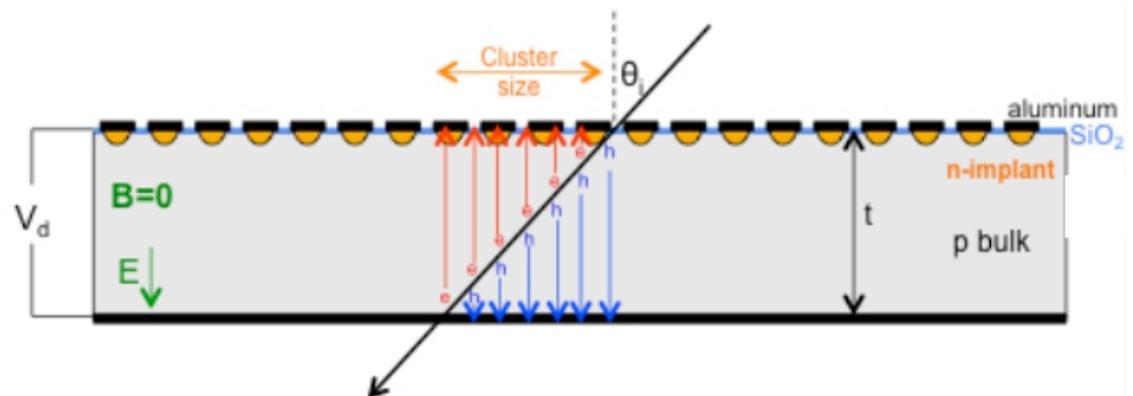
- **Detector efficiency** : probability to detect a transversing particle
  - should be as close to 100% as possible
  - i.e. 6 layer silicon detector with 98% efficiency per layer -- > overall tracking efficiency is below 90%
  - needs to be measured in test beam

$$\epsilon_{\text{track}} = (\epsilon_{\text{layer}})^n$$

n = number of layer is tracking system

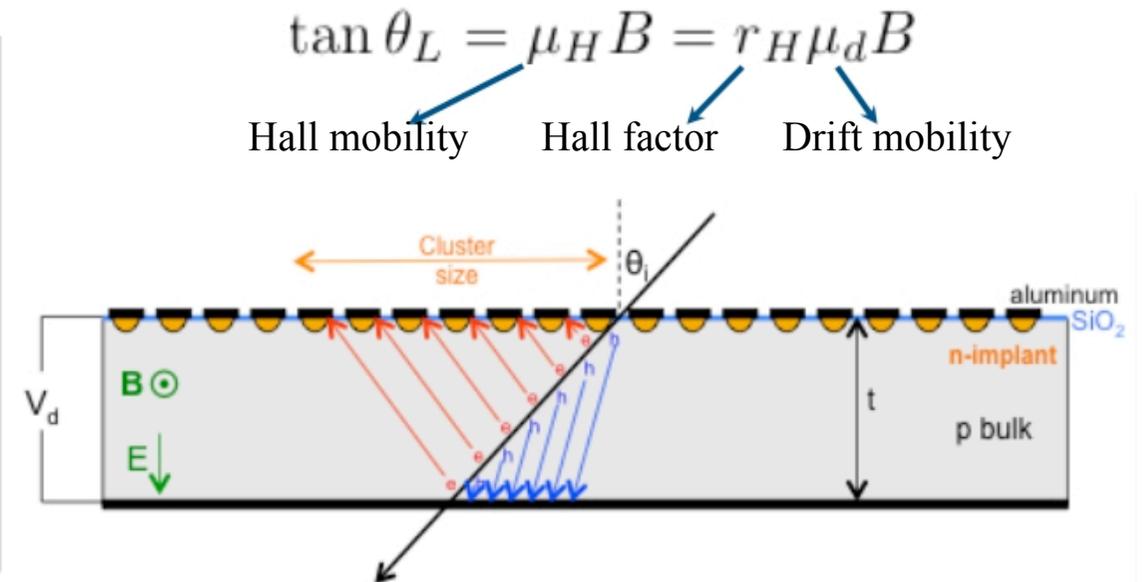
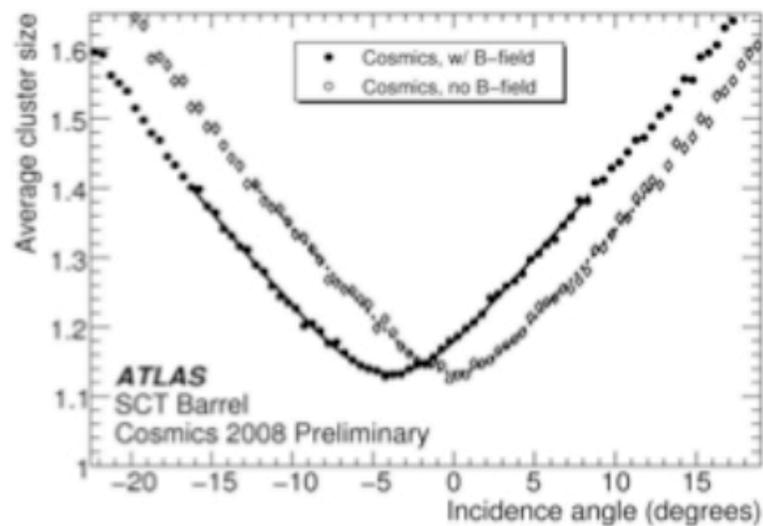
- **Cluster size** : number of hit pixels/strips belonging to one track
  - usually given in unit of strips or pixels
  - depending on angle of incidence

Needs to be measured in test beam ....



# Lorentz Angle

- increase of cluster size due to Lorentz drift in a magnetic field
- Important parameter in particle physics as most tracking detectors operate in a magnetic field



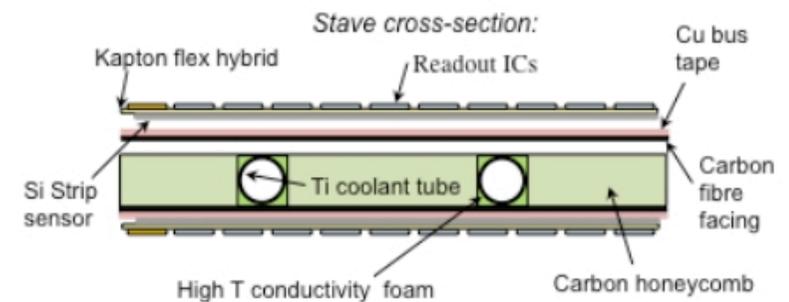
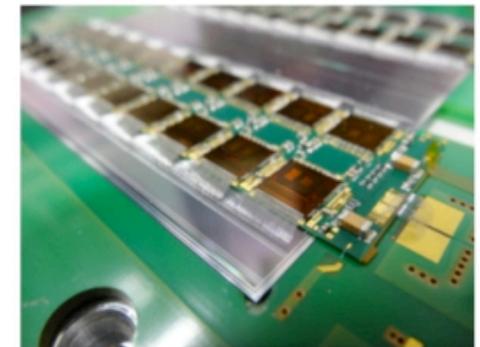
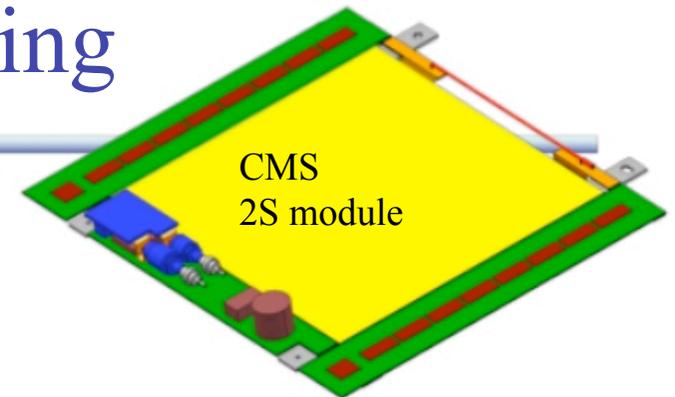
Measurement in ATLAS after full installation

Needs to be measured in test beam AND magnetic field ....

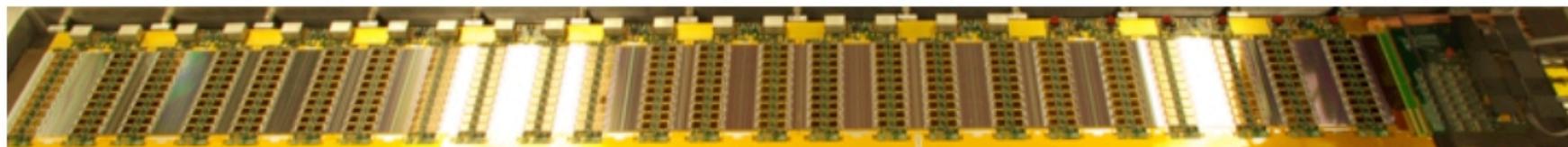
- as cluster size, drift velocity and depletion voltage are depending on radiation damage this changes with the accumulated irradiation (fluence)

# Next Generation Tracking

- ATLAS&CMS plan for  $\sim 200 \text{ m}^2$  silicon strip detector
- Commonalities:
  - 20000 modules to be produced
  - choice of sensor technology (n-- in-- p)
  - radiation level ( $10^{15} \text{ neq/cm}^2$ )
- CMS:
  - modules discriminate low--  $p_T$  tracks in the FE electronics
  - hybrid is key element: Wire-- bonds from the sensors to the hybrid on the two sides
- ATLAS:
  - stave concept where silicon is directly glued onto carbon fibre



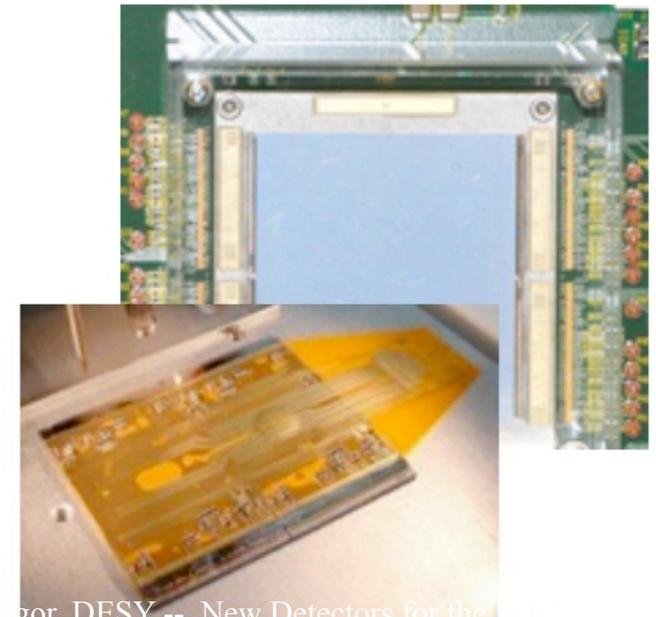
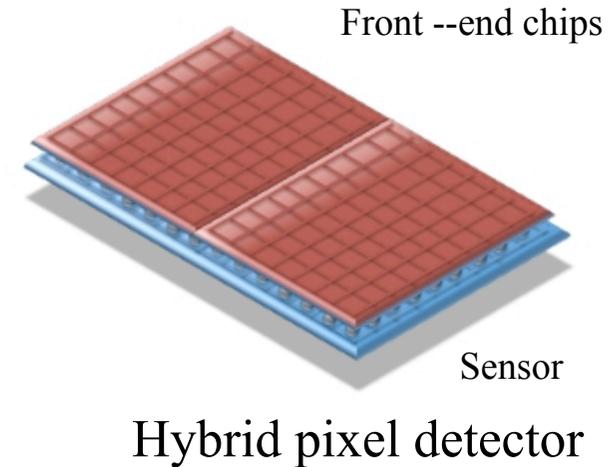
1.4 m



ATLAS Prototype for barrel strip stave

# ATLAS and CMS Pixel Detectors

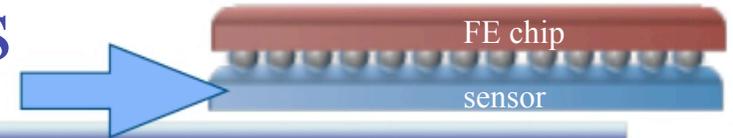
- The requirement of radiation tolerance is particularly demanding for the Inner Pixel:
  - ~16 x hit rates (occupancy)
  - 2-- 4 x better resolution needed (smaller pixel)
  - 10 x readout rates
  - >10 x radiation tolerance (new sensors and electronics needed)
  - increased forward coverage
  - less material ...
- Current pixel layout for ATLAS and CMS based on existing solutions
  - hybrid pixel approach with standard or novel sensors under investigation.
  - read-- out chips in 65 nm technology.
  - alternatives emerging
- **Several more years of R&D allow the use of more performant technologies.**



Example : ATLAS quad modules

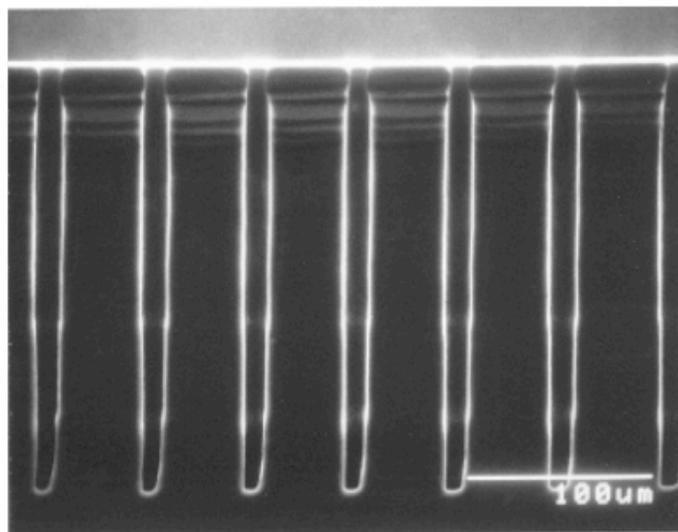


# New Technologies

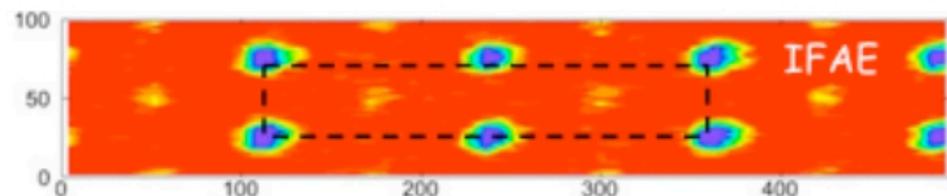
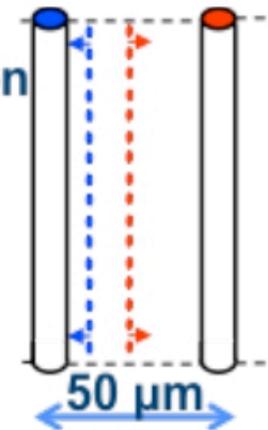
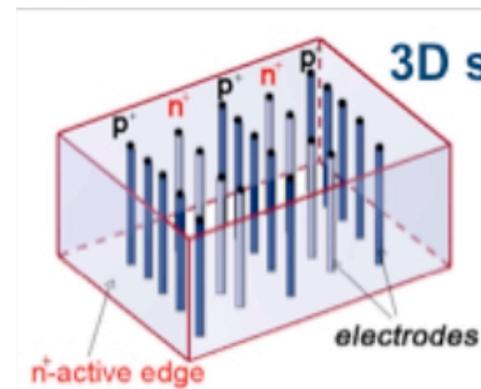


## 3D Silicon

- Both electrode types are processed inside the detector bulk
- Charge collected by implants in pixels
  - max. drift and depletion distance set by electrode spacing
  - reduced collection time and depletion voltage
  - low charge sharing
  - lower leakage current and power dissipation
  - radiation tolerant
- First use case -- > ATLAS IBL



bam



Efficiency measured

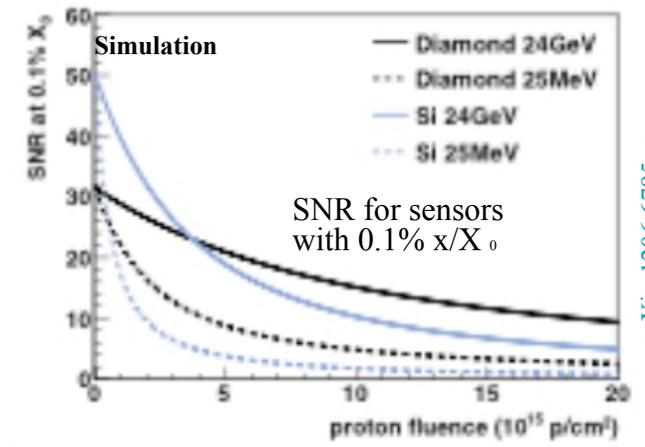
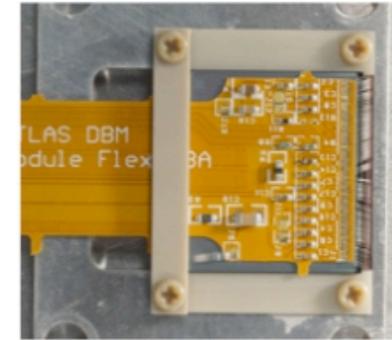
at test

# New Technologies



## Diamond Sensors

- Chemical vapor deposition (CVD) diamond
  - band gap 5.5 eV (silicon: 1.1 eV)
  - displacement energy 42 eV/atom (silicon: 15 eV)
  - only 60% as many charge carriers as silicon
  - radiation tolerant
  - low Z
- Some issues:
  - availability (only two suppliers)
  - reduced charge collection after irradiation
  - difficulties with bump bonding



arXiv:1206.6795

**Future:**  
Combination of 3D  
and pCVD

# New Alternative: CMOS

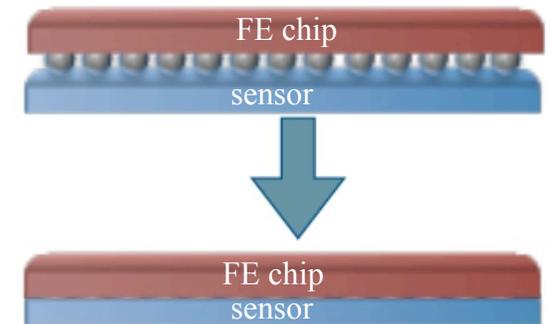
- Use of commercial CMOS technologies for replacement of sensor or even full hybrid (monolithic)
  - possible advantages: integration, cost, power consumption and material budget
  - currently in two experiments: DEPFET in Belle-- II and MAPS in STAR but only for moderate radiation suited

- **Classical CMOS sensors:**

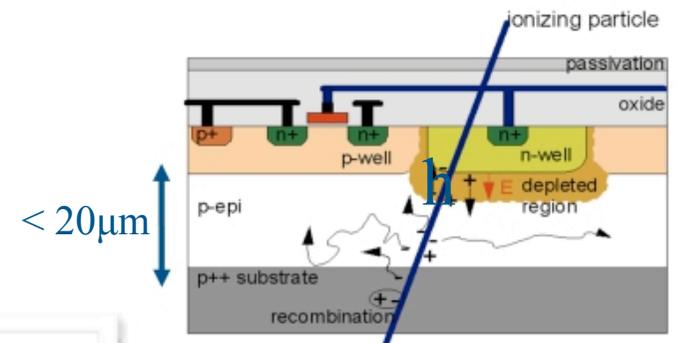
- typically no backside processes
- signal charge collection mainly by diffusion
  - > moderate radiation tolerance ( diffusion is suppressed by trapping  $< 10^{15} \text{ neq/cm}^2$ )

**Main challenge for HL-- LHC:** need combination of

- tolerance to displacement damage (depletion)
- integration of complex circuitry without efficiency loss
- keep using commercial technology



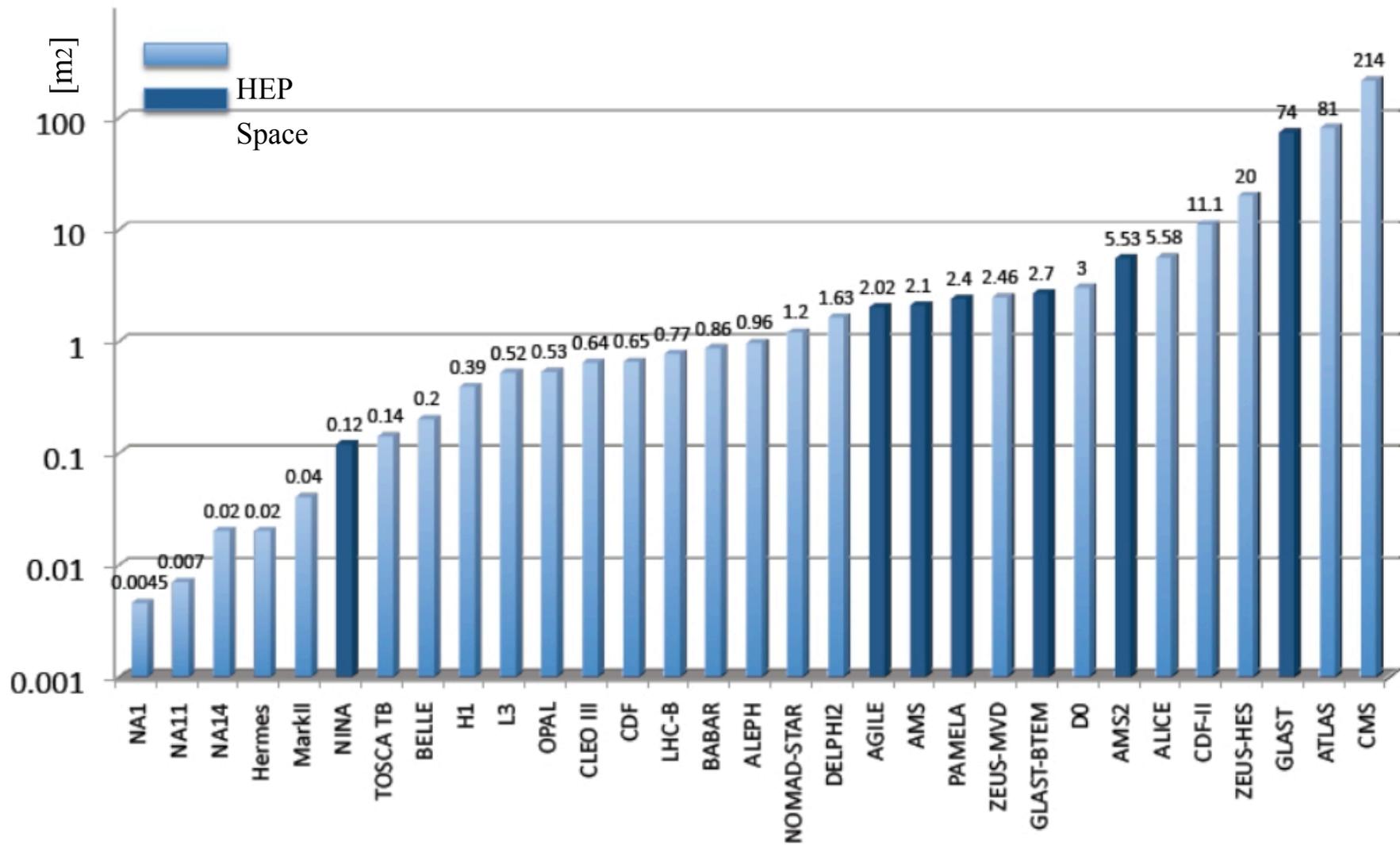
Monolithic = front --end electronics on same substrate as active sensor



“Classic” CMOS sensor based on diffusion  
Mimosa



# Silicon detector size 1981 -- 2006



# Summary

- Semiconductor detectors play a central role in modern high energy and photon physics
- Used in tracking detectors for position and momentum measurements of charged particles and for reconstruction of vertices (specially pixel detectors)
- By far the most important semiconductor: Silicon, indirect band gap 1.1 eV, however: 3.6 eV necessary to form e-h pair
- Advantages Si: large yield in generated charge carriers, fine segmentation, radiation tolerant, mechanically stable, ...
- Working principle (general): diode in reverse bias (pn junction)
- Important : S/N has to be good. Noise  $\sim 1/C$  for systems that measure signal charge, smaller feature sizes are good. Pixel!
- Pixel detectors are used in most major current particle detectors and are planned for future experiment
- R&D for semiconductor detectors always has to be on the edge of technology

